

Supporting information

Development of a novel Eu^{2+} activated oxonitridosilicate cyan phosphor for enhancing the color quality of violet-chip-based white LED

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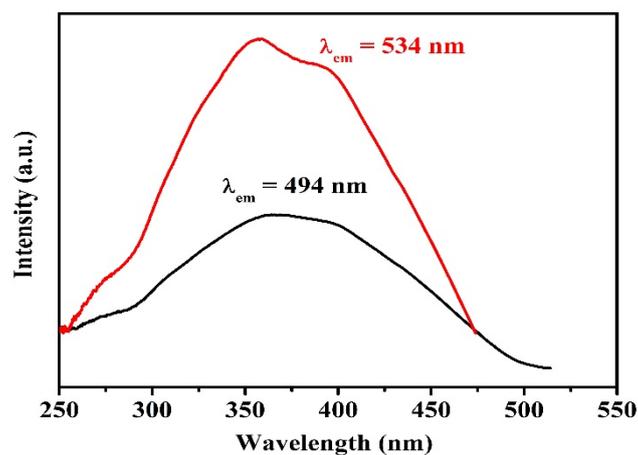


Figure S1 Excitation spectra monitored at 494 and 534 nm of LSANO:0.01Eu²⁺ sample.

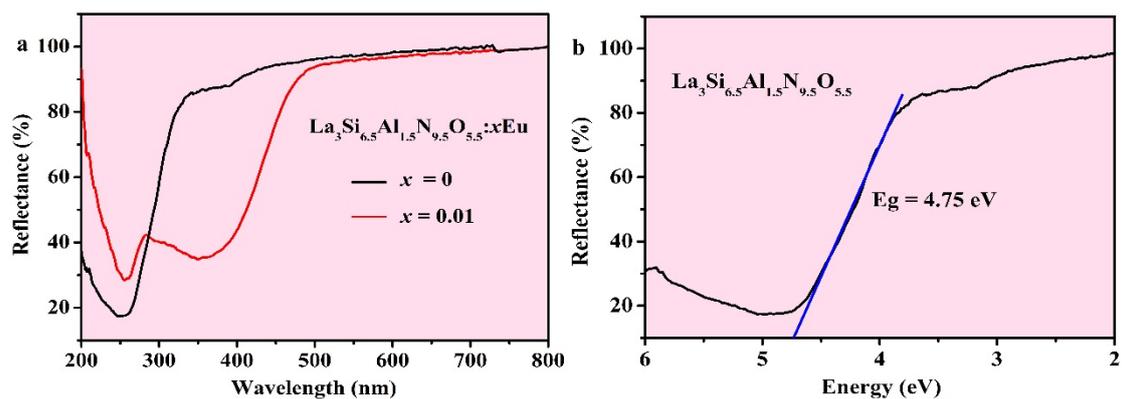


Figure S2 (a) Diffuse reflectance spectra of Eu-doped and non-doped LSANO samples; (b) optical absorption edge of the LSANO.

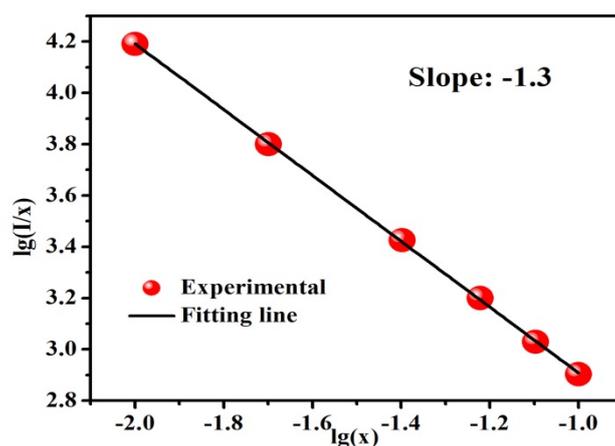


Figure S3 Dependence of $\text{Log}(I/x)$ versus $\text{Log}(x)$ and the linear fitting (Here, the luminescence intensity I is integral intensity).

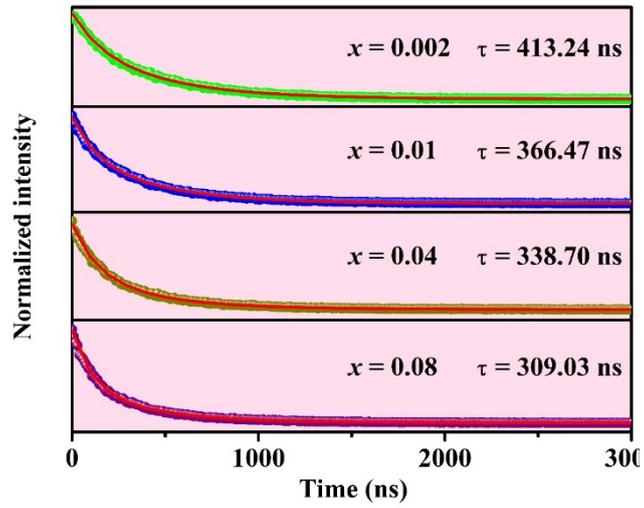


Figure S4 PL decay curves of LSANO: $x\text{Eu}^{2+}$ ($x = 0.002, 0.01, 0.04$ and 0.08) phosphors.

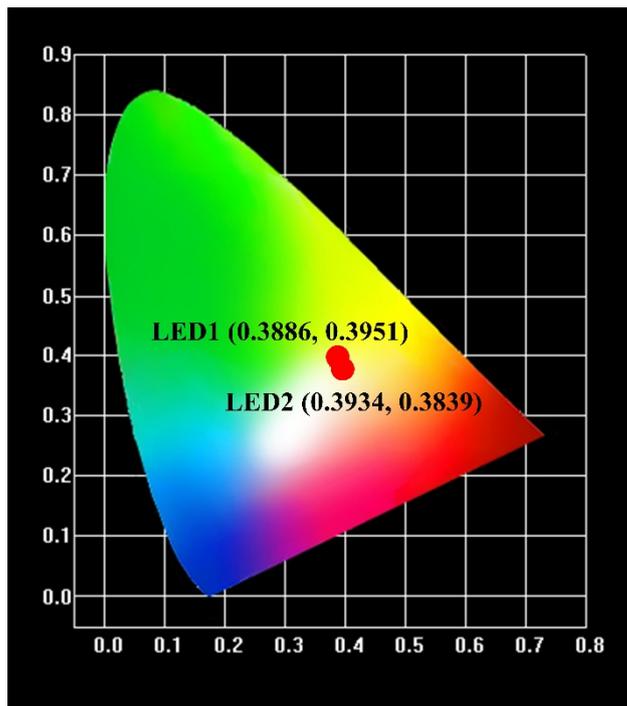


Figure S5 Chromaticity coordinates of the white LEDs in the CIE chromaticity diagram.

Tables

Table S1 Significant parameters of LSANO:0.01Eu²⁺

Crystallographic data of LSANO:0.01Eu ²⁺	
2θ range/deg.	10 – 80
T/K	298
symmetry	monoclinic
space group	I2/a
$a/\text{\AA}$	15.862
$b/\text{\AA}$	4.914
$c/\text{\AA}$	18.074
$\alpha/\text{deg.}$	90°
$\beta/\text{deg.}$	115.043°
$\gamma/\text{deg.}$	90°
Volume/ \AA^3	1276.391
$R_p/\%$	4.32
$R_{wp}/\%$	5.26
χ^2	2.332

Measurements and characterization: The phases of samples were identified using powder X-ray diffraction (XRD) analysis (Bruker AXS D8), with graphite monochromatized Cu K α radiation ($\lambda = 0.15405$ nm) operating at 40 kV and 40 mA. The scanning rate was 10°min^{-1} with a step size of 0.02° . The morphology and chemical composition of the powders was investigated by field emission scanning electron microscopy (SEM) equipped with an energy-dispersive (EDS) spectrometer (S-4800, Hitachi, Japan). Transmission electron microscopy (TEM) was taken on a FEI Tecnai G2S-Twin with a field-emission gun operating at 200 kV. X-ray photoelectron spectroscopy (XPS) spectra were obtained from a VG ESCALABMK II electron spectrometer. PLE and PL spectra were measured at room temperature by a Hitachi F7000 spectrophotometer equipped with a 150 W xenon lamp under a working voltage of 400 V, with a spectral slit width of 2.5 nm. The diffuse-reflectance spectra were measured by a Hitachi U-4100 spectrophotometer. The PL decay curves were detected by a Lecroy Wave Runner 6100 digital oscilloscope (1 GHz) using a tunable laser (pulse width = 4 ns, gate = 50 ns) as the excitation source (Continuum Sunlite OPO). The temperature-dependent luminescence spectra were measured in the range of 7 – 475 K with a fluorescence spectrophotometer, using a 450 W Xe lamp as an excitation source (Edinburgh Instruments FLSP-920) with a temperature controller.